Special Issue

Computer-Aided Image Processing and Analysis

Message from the Guest Editor

The last decade has witnessed the remarkable progress of computer-aided image processing and analysis technology. Recently, deep learning has yielded a qualitative leap in this field. However, increasing attention has been paid to the potential drawbacks of the deep learning architecture, e.g., the high cost of the computability and data. Moreover, it is difficult to analytically explain the super-performance of deep learning that works like a "black box". It is now the time to reconsider the future development of image processing and analysis.

Recently, explainable models have attracted increasing attention. For example, explainable networks, bio-inspired models, and have demonstrated promising performance in many areas, which indicates a potential direction for future research efforts. Therefore, this Special Issue is intended for the presentation of new ideas and experimental results in the field of explainable models and their applications in image processing and analysis. The comparisons between the explainable models and "black box" models are especially encouraged.

Guest Editor

Dr. Zhe Chen

College of Computer and Information Engineering, Hohai University, Nanjing 211100, China

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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